## Notice of References Cited

Application/Control No.

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Examiner

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Applicant(s)/Patent Under
Reexamination
FRANKE ET AL.

Art Unit
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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0218866 A1	11-2003	Chen et al.	361/704
	В	US-2004/0091311 A1	05-2004	Lin, Jen-Cheng	403/322.4
	С	US-5,526,874	06-1996	White, Nikolas F.	165/80.3
	D	US-6,430,051 B1	08-2002	Yang et al.	361/704
	E	US-6,466,445 B1	10-2002	Chen, Chun-Chi	361/704
	F	US-6,507,489 B1	01-2003	McGowan et al.	361/687
	G	US-6,522,545 B2	02-2003	Shia et al.	361/704
	Н	US-6,542,367 B2	04-2003	Shia et al.	361/703
	ı	US-6,545,870 B1	04-2003	Franke et al.	361/704
	J	US-6,563,716 B1	05-2003	Truong et al.	361/816
	К	US-6,668,431 B2	12-2003	Franke et al.	24/458
	L	US-6,711,019 B2	03-2004	Manabe et al.	361/704
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	z					
	0					
	Р					
	Ö					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.